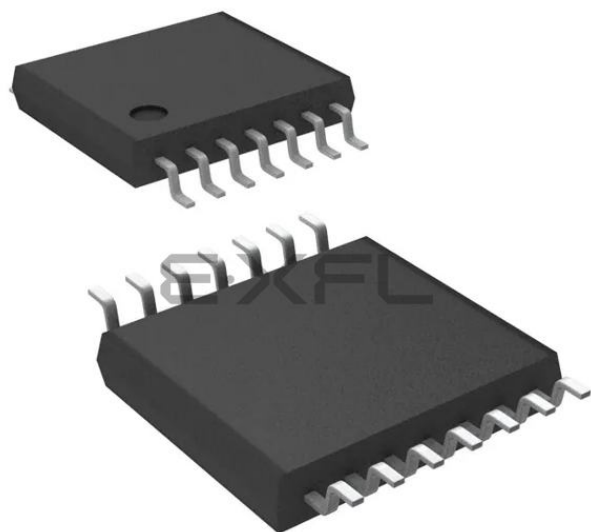




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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Not For New Designs
Core Processor	R8C
Core Size	16-Bit
Speed	20MHz
Connectivity	UART/USART
Peripherals	POR, PWM, Voltage Detect, WDT
Number of I/O	11
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512 x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 5x10b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	14-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	14-TSSOP
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f2m112ansp-w4

Table 1.2 lists the R8C/M11A Group Register Settings. These settings correspond to the specification differences between the R8C/M11A Group and R8C/M12A Group.

Table 1.2 R8C/M11A Group Register Settings

Related Function	Register Name	Address	Bit	Setting Method for Access
INT3	INTEN	00038h	INT3EN	Reserved bit. Set to 0.
	INTF0	0003Ah	INT3F0, INT3F1	Reserved bits. Set to 0.
	ISCR0	0003Ch	INT3SA, INT3SB	Reserved bits. Set to 0.
	ILVLD	0004Dh	ILVLD0, ILVLD1	Reserved bits. Set to 0.
	IRR3	00053h	IRI3	Reserved bit. Set to 0.
KI0	KIEN	0003Eh	KI0EN, KI0PL	Reserved bits. Set to 0.
Comparator B3 interrupt	ILVL2	00042h	ILVL24, ILVL25	Reserved bits. Set to 0.
	IRR2	00052h	IRCMP3	Reserved bit. Set to 0.
P1_0	PD1	000A9h	PD1_0	Reserved bit. Set to 0.
	P1	000AFh	P1_0	Reserved bit. Set to 0.
	PUR1	000B5h	PU1_0	Reserved bit. Set to 0.
	POD1	000C1h	POD1_0	Reserved bit. Set to 0.
	PML1	000C8h	P10SEL0, P10SEL1	Reserved bits. Set to 0.
P3_3, P3_4, P3_5	PD3	000ABh	PD3_3, PD3_4, PD3_5	Reserved bits. Set to 0.
	P3	000B1h	P3_3, P3_4, P3_5	Reserved bits. Set to 0.
	PUR3	000B7h	PU3_3, PU3_4, PU3_5	Reserved bits. Set to 0.
	DRR3	000BDh	DRR3_3, DRR3_4, DRR3_5	Reserved bits. Set to 0.
	POD3	000C3h	POD3_3, POD3_4, POD3_5	Reserved bits. Set to 0.
	PML3	000CCh	P33SEL0, P33SEL1	Reserved bits. Set to 0.
	PMH3	000CDh	P34SEL0, P34SEL1, P35SEL0, P35SEL1	Reserved bits. Set to 0.
P4_2, P4_5	PD4	000ACh	PD4_2, PD4_5	Reserved bits. Set to 0.
	P4	000B2h	P4_2, P4_5	Reserved bits. Set to 0.
	PUR4	000B8h	PU4_2, PU4_5	Reserved bits. Set to 0.
	POD4	000C4h	POD4_2, POD4_5	Reserved bits. Set to 0.
	PML4	000CEh	P42SEL0, P42SEL1	Reserved bits. Set to 0.
	PMH4	000CFh	P45SEL0, P45SEL1	Reserved bits. Set to 0.
AN0	ADINSEL	0009Dh	CH0, ADGSEL0, ADGSEL1	Do not set to 000.
Comparator B3	WCMPR	00180h	WCB3M0, WCB3OUT	Reserved bits. Set to 0.
	WCB3INTR	00182h	All bits	Reserved register. No access is allowed.

1.1.3 Specifications

Tables 1.3 and 1.4 outline the Specifications.

Table 1.3 Specifications (1)

Item	Function	Description
CPU	Central processing unit	R8C CPU core • Number of fundamental instructions: 89 • Minimum instruction execution time: 50 ns ($f(XIN) = 20\text{ MHz}$, $VCC = 2.7\text{ V to }5.5\text{ V}$) 200 ns ($f(XIN) = 5\text{ MHz}$, $VCC = 1.8\text{ V to }5.5\text{ V}$) • Multiplier: 16 bits $\times$ 16 bits $\rightarrow$ 32 bits • Multiply-accumulate instruction: 16 bits $\times$ 16 bits + 32 bits $\rightarrow$ 32 bits • Operating mode: Single-chip mode (address space: 1 Mbyte)
Memory	ROM, RAM, data flash	See Table 1.5 Product List .
Reset sources		• Hardware reset by $\overline{\text{RESET}}$ • Power-on reset • Watchdog timer reset • Software reset • Reset by voltage detection 0
Voltage detection	Voltage detection circuit	Voltage detection with two check points: Voltage detection 0, voltage detection 1 (detection levels selectable)
Watchdog timer		• 14 bits $\times$ 1 (with prescaler) • Reset start function selectable • Count source protection function selectable • Periodic timer function selectable
Clock	Clock generation circuits	• 3 circuits: XIN clock oscillation circuit, high-speed on-chip oscillator (with frequency adjustment function), low-speed on-chip oscillator • Oscillation stop detection: XIN clock oscillation stop detection function • Clock frequency divider circuit integrated
Power control		• Standard operating mode • Wait mode (CPU stopped, peripheral functions in operation) • Stop mode (CPU and peripheral functions stopped)
Interrupts		• Number of interrupt vectors: 69 • External interrupt inputs: 8 ($\overline{\text{INT}} \times 4$, key input $\times 4$) • Priority levels: 2
I/O ports	Programmable I/O ports	• CMOS I/O: 17 (pull-up resistor selectable) • High-current drive ports: 8
Timer	Timer RJ2	16 bits $\times$ 1 Timer mode, pulse output mode (output level inverted every period), event counter mode, pulse width measurement mode, pulse period measurement mode
	Timer RB2	8 bits $\times$ 1 (with 8-bit prescaler) or 16 bits $\times$ 1 (selectable) Timer mode, programmable waveform generation mode (PWM output), programmable one-shot generation mode, programmable wait one-shot generation mode
	Timer RC	16 bits $\times$ 1 (with 4 capture/compare registers) Timer mode (output compare function, input capture function), PWM mode (3 outputs), PWM2 mode (1 PWM output)
Serial interface	UART0	Clock synchronous serial I/O. Also used for asynchronous serial I/O.
A/D converter		• Resolution: 10 bits $\times$ 6 channels • Sample and hold function, sweep mode
Comparator B		2 circuits

Table 1.4 Specifications (2)

Item	Function	Description
Flash memory		• Program/erase voltage for program ROM: VCC = 1.8 V to 5.5 V • Program/erase voltage for data flash: VCC = 1.8 V to 5.5 V • Program/erase endurance: 10,000 times (data flash) 10,000 times (program ROM) • Program security: ID code check, protection enabled by lock bit • Debug functions: On-chip debug, on-board flash rewrite function
Operating frequency/ Power supply voltage		f(XIN) = 20 MHz (VCC = 2.7 V to 5.5 V) f(XIN) = 5 MHz (VCC = 1.8 V to 5.5 V)
Temperature range		-20 °C to 85 °C (N version) -40 °C to 85 °C (D version) ⁽¹⁾
Package		14-pin TSSOP: [Package code] PTSP0014JA-B 14-pin DIP: [Package code] PRDP0014AC-A 20-pin LSSOP: [Package code] PLSP0020JB-A 20-pin DIP: [Package code] PRDP0020AD-A

Note:

1. Specify the D version if it is to be used.

1.2 Product List

Table 1.5 lists the Product List. Figure 1.1 shows the Product Part Number Structure.

Table 1.5 Product List

Current of May 2012

Group Name	Part No.	Internal ROM Capacity		Internal RAM Capacity	Package Type	Remarks
		Program ROM	Data Flash			
R8C/M11A Group	R5F2M110ANSP	2 Kbytes	1 Kbyte × 2	256 bytes	PTSP0014JA-B	N version
	R5F2M111ANSP	4 Kbytes	1 Kbyte × 2	384 bytes		
	R5F2M112ANSP	8 Kbytes	1 Kbyte × 2	512 bytes		
	R5F2M110ANDD	2 Kbytes	1 Kbyte × 2	256 bytes	PRDP0014AC-A	
	R5F2M111ANDD	4 Kbytes	1 Kbyte × 2	384 bytes		
	R5F2M112ANDD	8 Kbytes	1 Kbyte × 2	512 bytes		
	R5F2M110ADSP	2 Kbytes	1 Kbyte × 2	256 bytes	PTSP0014JA-B	D version
	R5F2M111ADSP	4 Kbytes	1 Kbyte × 2	384 bytes		
	R5F2M112ADSP	8 Kbytes	1 Kbyte × 2	512 bytes		
R8C/M12A Group	R5F2M120ANSP	2 Kbytes	1 Kbyte × 2	256 bytes	PLSP0020JB-A	N version
	R5F2M121ANSP	4 Kbytes	1 Kbyte × 2	384 bytes		
	R5F2M122ANSP	8 Kbytes	1 Kbyte × 2	512 bytes		
	R5F2M120ANDD	2 Kbytes	1 Kbyte × 2	256 bytes	PRDP0020AD-A	
	R5F2M121ANDD	4 Kbytes	1 Kbyte × 2	384 bytes		
	R5F2M122ANDD	8 Kbytes	1 Kbyte × 2	512 bytes		
	R5F2M120ADSP	2 Kbytes	1 Kbyte × 2	256 bytes	PLSP0020JB-A	D version
	R5F2M121ADSP	4 Kbytes	1 Kbyte × 2	384 bytes		
	R5F2M122ADSP	8 Kbytes	1 Kbyte × 2	512 bytes		

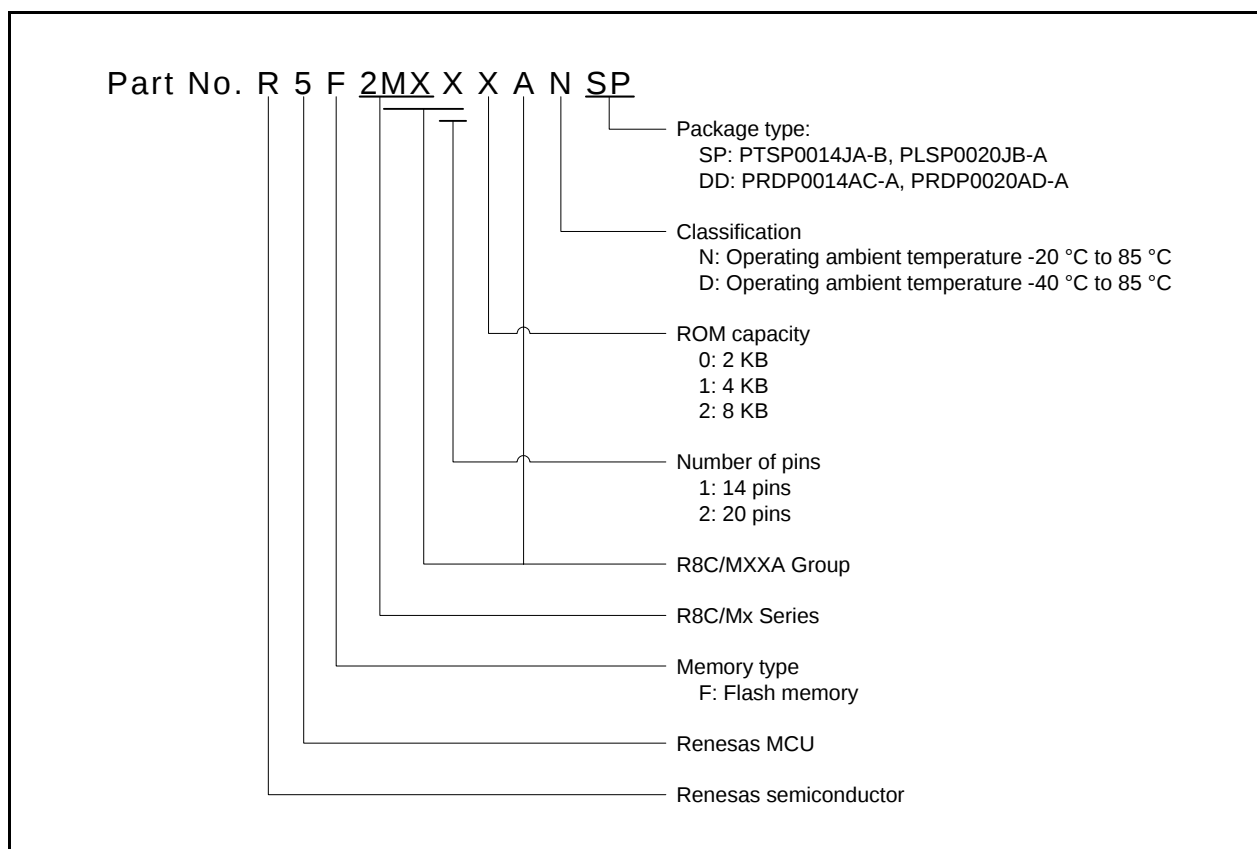


Figure 1.1 Product Part Number Structure

1.5 Pin Functions

Table 1.7 lists the Pin Functions.

Table 1.7 Pin Functions

Item	Pin Name	I/O	Description
Power supply input	VCC, VSS	—	Apply 1.8 V through 5.5 V to the VCC pin. Apply 0 V to the VSS pin.
Analog power supply input	AVCC, AVSS	—	Power supply input for the A/D converter. Connect a capacitor between pins AVCC and AVSS.
Reset input	$\overline{\text{RESET}}$	I	Applying a low level to this pin resets the MCU.
MODE	MODE	I	Connect this pin to the VCC pin via a resistor.
XIN clock input	XIN	I	I/O for the XIN clock generation circuit.
XIN clock output	XOUT	O	Connect a ceramic resonator or a crystal oscillator between pins XIN and XOUT. ⁽¹⁾ To use an external clock, input it to the XIN pin. P4_7 can be used as an I/O port at this time.
$\overline{\text{INT}}$ interrupt input	$\overline{\text{INT0}}$ to $\overline{\text{INT3}}$	I	$\overline{\text{INT}}$ interrupt input.
Key input interrupt	$\overline{\text{KI0}}$ to $\overline{\text{KI3}}$	I	Key input interrupt input.
I/O ports	P1_0 to P1_7, P3_0 to P3_5, P3_7, P4_2, P4_5 to P4_7, PA_0	I/O	CMOS I/O ports. Each port has an I/O select direction register, enabling switching input and output for each port. For input ports other than PA_0, the presence or absence of a pull-up resistor can be selected by a program. P1_2 to P1_5, P3_3 to P3_5, and P3_7 can be used as LED drive ports.
Timer RJ2	TRJIO	I/O	Timer RJ2 I/O.
	TRJO	O	Timer RJ2 output.
Timer RB2	TRBO	O	Timer RB2 output.
Timer RC	TRCCLK	I	External clock input.
	TRCTRG	I	External trigger input.
	TRCIOA, TRCIOB, TRCIOC, TRCIOD	I/O	Timer RC I/O.
Serial interface	CLK0	I/O	Transfer clock I/O.
	RXD0	I	Serial data input.
	TXD0	O	Serial data output.
A/D converter	AN0 to AN4, AN7	I	Analog input for the A/D converter.
	ADTRG	I	External trigger input for the A/D converter.
Comparator B	IVCMP1, IVCMP3	I	Analog voltage input for comparator B.
	IVREF1, IVREF3	I	Reference voltage input for comparator B.
	VCOUT1, VCOUT3	O	Comparison result output for comparator B.

Note:

1. Contact the oscillator manufacturer for oscillation characteristics.

3. Address Space

3.1 Memory Map

Figure 3.1 shows the Memory Map. The R8C/M11A Group and R8C/M12A Group have a 1-Mbyte address space from addresses 00000h to FFFFFh. The internal ROM (program ROM) is allocated at lower addresses, beginning with address 0FFFFh. For example, an 8-Kbyte internal ROM area is allocated at addresses 0E000h to 0FFFFh. The fixed interrupt vector table is allocated at addresses 0FFDCh to 0FFFFh. The start address of each interrupt routine is stored here.

The internal ROM (data flash) is allocated at addresses 03000h to 037FFh.

The internal RAM is allocated at higher addresses, beginning with address 00400h. For example, a 512-byte internal RAM area is allocated at addresses 00400h to 005FFh. The internal RAM is used not only for data storage but also as a stack area when a subroutine is called or when an interrupt request is acknowledged.

Special function registers (SFRs) are allocated at addresses 00000h to 002FFh. Peripheral function control registers are allocated here. All unallocated spaces within the SFRs are reserved and cannot be accessed by users.

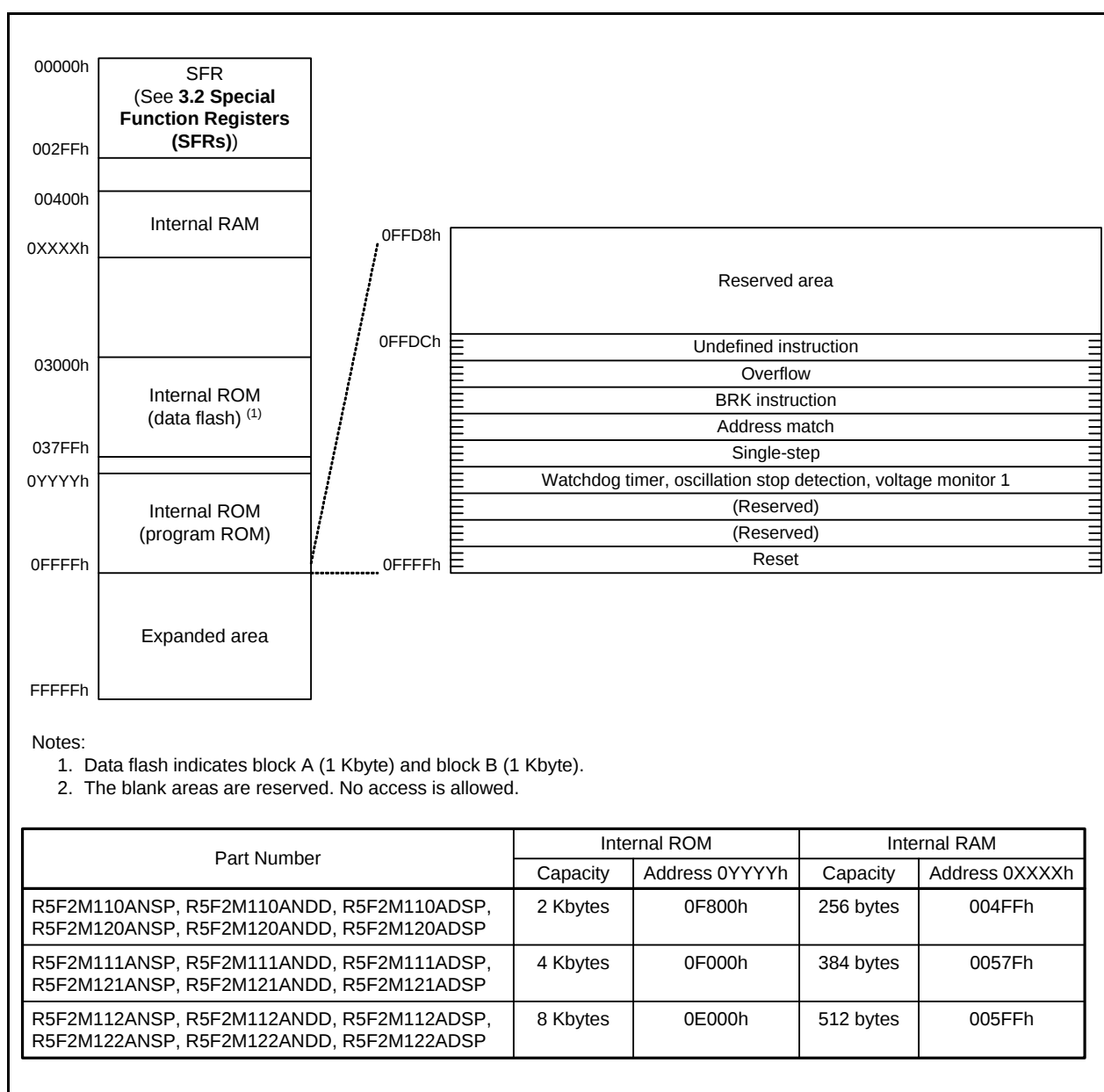


Figure 3.1 Memory Map

Table 3.5 SFR Information (5) (1)

Address	Register Name	Symbol	After Reset
00100h			
00101h			
00102h			
00103h			
00104h			
00105h			
00106h			
00107h			
00108h			
00109h			
0010Ah			
0010Bh			
0010Ch			
0010Dh			
0010Eh			
0010Fh			
00110h			
00111h			
00112h			
00113h			
00114h			
00115h			
00116h			
00117h			
00118h			
00119h			
0011Ah			
0011Bh			
0011Ch			
0011Dh			
0011Eh			
0011Fh			
00120h			
00121h			
00122h			
00123h			
00124h			
00125h			
00126h			
00127h			
00128h			
00129h			
0012Ah			
0012Bh			
0012Ch			
0012Dh			
0012Eh			
0012Fh			
00130h			
00131h			
00132h			
00133h			
00134h			
00135h			
00136h			
00137h			
00138h			
00139h			
0013Ah			
0013Bh			
0013Ch			
0013Dh			
0013Eh			
0013Fh			

Note:

1. The blank areas are reserved. No access is allowed.

Table 3.7 SFR Information (7) (1)

Address	Register Name	Symbol	After Reset
00180h	Comparator B Control Register	WCMPR	00h
00181h	Comparator B1 Interrupt Control Register	WCB1INTR	00h
00182h	Comparator B3 Interrupt Control Register	WCB3INTR	00h
00183h			
00184h			
00185h			
00186h			
00187h			
00188h			
00189h			
0018Ah			
0018Bh			
0018Ch			
0018Dh			
0018Eh			
0018Fh			
00190h			
00191h			
00192h			
00193h			
00194h			
00195h			
00196h			
00197h			
00198h			
00199h			
0019Ah			
0019Bh			
0019Ch			
0019Dh			
0019Eh			
0019Fh			
001A0h			
001A1h			
001A2h			
001A3h			
001A4h			
001A5h			
001A6h			
001A7h			
001A8h			
001A9h	Flash Memory Status Register	FST	10000000b
001AAh	Flash Memory Control Register 0	FMR0	00h
001ABh	Flash Memory Control Register 1	FMR1	00h
001ACh	Flash Memory Control Register 2	FMR2	00h
001ADh	Flash Memory Refresh Control Register	FREFR	00h
001AEh			
001AFh			
001B0h			
001B1h			
001B2h			
001B3h			
001B4h			
001B5h			
001B6h			
001B7h			
001B8h			
001B9h			
001BAh			
001BBh			
001BCh			
001BDh			
001BEh			
001BFh			

Note:

1. The blank areas are reserved. No access is allowed.

4. Electrical Characteristics

Table 4.1 Absolute Maximum Ratings

Symbol	Parameter		Condition	Rated Value	Unit
V _{CC} /AV _{CC}	Power supply voltage			-0.3 to 6.5	V
V _i	Input voltage	XIN	XIN-XOUT oscillation on (oscillation circuit used) ⁽¹⁾	-0.3 to 1.9	V
			XIN-XOUT oscillation off (oscillation circuit not used) ⁽¹⁾	-0.3 to V _{CC} + 0.3	V
		Other pins		-0.3 to V _{CC} + 0.3	V
V _o	Output voltage	XOUT	XIN-XOUT oscillation on (oscillation circuit used) ⁽¹⁾	-0.3 to 1.9	V
			XIN-XOUT oscillation off (oscillation circuit not used) ⁽¹⁾	-0.3 to V _{CC} + 0.3	V
		Other pins		-0.3 to V _{CC} + 0.3	V
P _d	Power consumption		-40 °C ≤ Topr ≤ 85 °C	500	mW
T _{opr}	Operating ambient temperature			-20 to 85 (N version)/ -40 to 85 (D version)	°C
T _{stg}	Storage temperature			-60 to 150	°C

Note:

1. When the oscillation circuit is used: bits CKPT1 to CKPT0 in the EXCKCR register are set to 11b
When the oscillation circuit is not used: bits CKPT1 to CKPT0 in the EXCKCR register are set to any value other than 11b

Table 4.5 Flash Memory (Program ROM) Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance ⁽²⁾		10,000 ⁽³⁾	—	—	times
—	Byte programming time (program/erase endurance ≤ 1,000 times)		—	80	—	μs
—	Byte programming time (program/erase endurance > 1,000 times)		—	160	—	μs
—	Block erase time		—	0.12	—	s
t _d (SR-SUS)	Transition time to suspend		—	—	0.25 + CPU clock × 3 cycles	ms
—	Time from suspend until erase restart		—	—	30 + CPU clock × 1 cycle	μs
t _d (CMDRST READY)	Time from when command is forcibly terminated until reading is enabled		—	—	30 + CPU clock × 1 cycle	μs
—	Program/erase voltage		1.8	—	5.5	V
—	Read voltage		1.8	—	5.5	V
—	Program/erase temperature		0	—	60	°C
—	Data hold time ⁽⁷⁾	Ambient temperature = 85 °C	10	—	—	years

Notes:

1. V_{cc} = 2.7 V to 5.5 V and T_{opr} = 0 °C to 60 °C, unless otherwise specified.
2. Definition of program/erase endurance
The number of program/erase cycles is defined on a per-block basis.
If the number of cycles is 10,000, each block can be erased 10,000 times.
For example, if 1,024 cycles of 1-byte-write are performed to different addresses in 1 Kbyte of block A, and then the block is erased, the number of cycles is counted as one. Note, however, that the same address must not be programmed more than once before completion of an erase (overwriting prohibited).
3. This indicates the number of times up to which all electrical characteristics can be guaranteed after the last programming/erase operation. Operation is guaranteed for any number of operations in the range of 1 to the specified minimum (Min).
4. In a system that executes multiple programming operations, the actual erase count can be reduced by shifting the write addresses in sequence and programming so that as much of the flash memory as possible is used before performing an erase operation. For example, when programming in 16-byte units, the effective number of rewrites can be minimized by programming up to 128 units before erasing them all in one operation. It is also advisable to retain data on the number of erase operations for each block and establish a limit for the number of erase operations performed.
5. If an error occurs during a block erase, execute a clear status register command and then a block erase command at least three times until the erase error does not occur.
6. For information on the program/erase failure rate, contact a Renesas technical support representative.
7. The data hold time includes the time that the power supply is off and the time the clock is not supplied.

Table 4.6 Flash Memory (Blocks A and B of Data Flash) Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance ⁽²⁾		10,000 ⁽³⁾	—	—	times
—	Byte programming time		—	150	—	μs
—	Block erase time		—	0.05	1	s
t _d (SR-SUS)	Time delay from suspend request until suspend		—	—	0.25 + CPU clock × 3 cycles	ms
—	Time from suspend until erase restart		—	—	30 + CPU clock × 1 cycle	μs
t _d (CMDRST-READY)	Time from when command is forcibly stopped until reading is enabled		—	—	30 + CPU clock × 1 cycle	μs
—	Program/erase voltage		1.8	—	5.5	V
—	Read voltage		1.8	—	5.5	V
—	Program/erase temperature		-20 (N version)	—	85	°C
			-40 (D version)	—	85	°C
—	Data hold time ⁽⁷⁾	Ambient temperature = 85 °C	10	—	—	years

Notes:

1. V_{CC} = 2.7 V to 5.5 V and Topr = -20 °C to 85 °C (N version)/-40 °C to 85 °C (D version), unless otherwise specified.
2. Definition of program/erase endurance
The number of program/erase cycles is defined on a per-block basis.
If the number of cycles is 10,000, each block can be erased 10,000 times.
For example, if 1,024 cycles of 1-byte-write are performed to different addresses in 1 Kbyte of block A, and then the block is erased, the number of cycles is counted as one. Note, however, that the same address must not be programmed more than once before completion of an erase (overwriting prohibited).
3. This indicates the number of times up to which all electrical characteristics can be guaranteed after the last programming/erase operation. Operation is guaranteed for any number of operations in the range of 1 to the specified minimum (Min).
4. In a system that executes multiple program operations, the actual erase count can be reduced by shifting the write addresses in sequence and programming so that as much of the flash memory as possible is used before performing an erase operation. For example, when programming in 16-byte units, the effective number of rewrites can be minimized by programming up to 128 units before erasing them all in one operation. It is also advisable to retain data on the number of erase operations for each block and establish a limit for the number of erase operations performed.
5. If an error occurs during a block erase, execute a clear status register command and then a block erase command at least three times until the erase error does not occur.
6. For information on the program/erase failure rate, contact a Renesas technical support representative.
7. The data hold time includes the time that the power supply is off and the time the clock is not supplied.

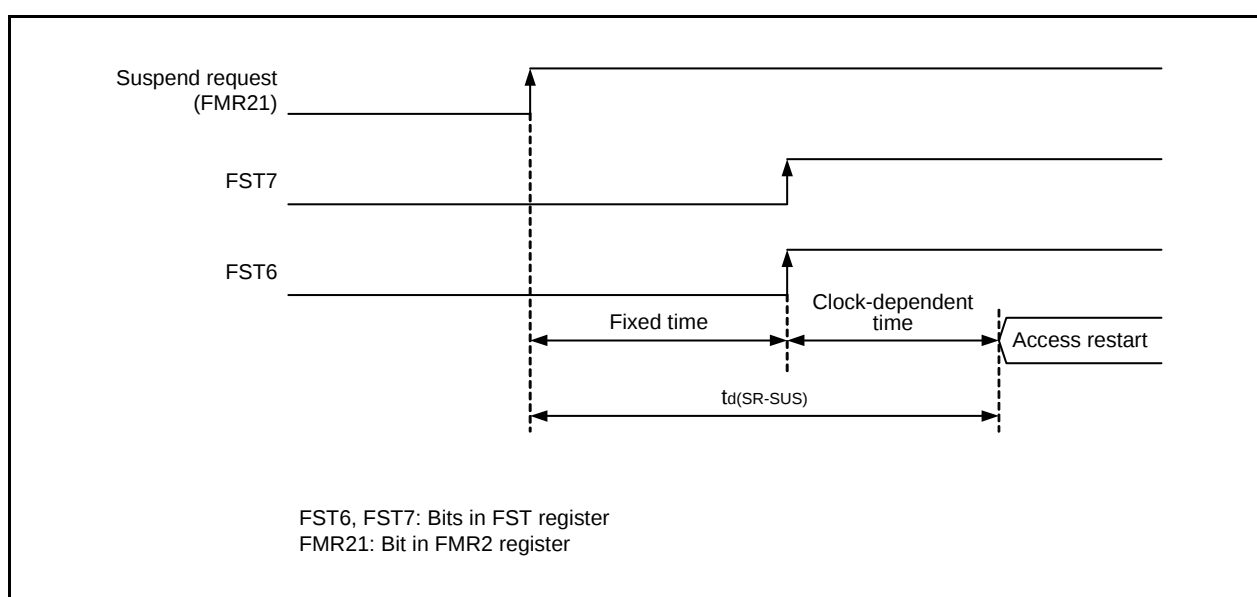
**Figure 4.2 Transition Time until Suspend**

Table 4.9 Power-On Reset Circuit (2)

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
t_{rth}	External power Vcc rise gradient		0	—	50,000	mV/msec

Notes:

1. The measurement condition is $T_{opr} = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$ (N version)/ $-40\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$ (D version), unless otherwise specified.
2. To use the power-on reset function, enable the voltage monitor 0 reset by setting the LVDAS bit in the OFS register to 0.

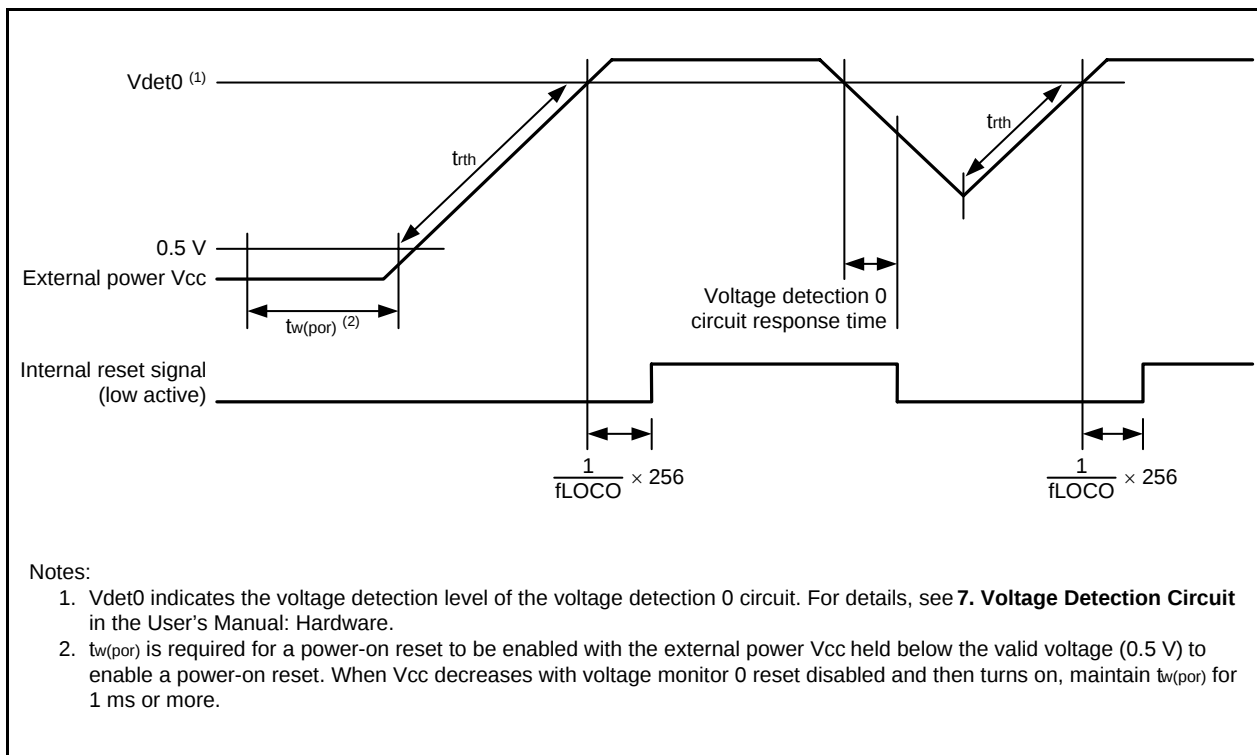
**Figure 4.3 Power-On Reset Circuit Electrical Characteristics**

Table 4.10 High-Speed On-Chip Oscillator Circuit Electrical Characteristics

Symbol	Parameter	Package	Condition	Standard			Unit
				Min.	Typ.	Max.	
—	High-speed on-chip oscillator frequency after reset is cleared	14-pin TSSOP 20-pin LSSOP	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$, $-20 \text{ }^{\circ}\text{C} \leq T_{opr} \leq 85 \text{ }^{\circ}\text{C}$	19.2	20.0	20.8	MHz
		14-pin DIP 20-pin DIP		19.0	20.0	21.0	MHz
		14-pin TSSOP 20-pin LSSOP	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$, $-40 \text{ }^{\circ}\text{C} \leq T_{opr} \leq 85 \text{ }^{\circ}\text{C}$	19.0	20.0	21.0	MHz
	High-speed on-chip oscillator frequency when the FR18S0 register adjustment value is written into the FRV1 register and the FR18S1 register adjustment value into the FRV2 register ⁽²⁾	14-pin TSSOP 20-pin LSSOP	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$, $-20 \text{ }^{\circ}\text{C} \leq T_{opr} \leq 85 \text{ }^{\circ}\text{C}$	17.694	18.432	19.169	MHz
		14-pin DIP 20-pin DIP		17.510	18.432	19.353	MHz
		14-pin TSSOP 20-pin LSSOP	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$, $-40 \text{ }^{\circ}\text{C} \leq T_{opr} \leq 85 \text{ }^{\circ}\text{C}$	17.510	18.432	19.353	MHz
—	Oscillation stabilization time	—	—	—	—	30	μs
—	Self power consumption at oscillation	—	$V_{CC} = 5.0 \text{ V}$, $T_{opr} = 25 \text{ }^{\circ}\text{C}$	—	530	—	μA

Notes:

1. $V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$, $T_{opr} = -20 \text{ }^{\circ}\text{C to } 85 \text{ }^{\circ}\text{C}$ (N version)/ $-40 \text{ }^{\circ}\text{C to } 85 \text{ }^{\circ}\text{C}$ (D version), unless otherwise specified.
2. This enables the setting errors of bit rates such as 9600 bps and 38400 bps to be 0 % when the serial interface is used in UART mode.

Table 4.11 Low-Speed On-Chip Oscillator Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
f _{LOCO}	Low-speed on-chip oscillator frequency	—	60	125	250	kHz
—	Oscillation stabilization time	—	—	—	35	μs
—	Self power consumption at oscillation	$V_{CC} = 5.0 \text{ V}$, $T_{opr} = 25 \text{ }^{\circ}\text{C}$	—	2	—	μA

Note:

1. $V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$, $T_{opr} = -20 \text{ }^{\circ}\text{C to } 85 \text{ }^{\circ}\text{C}$ (N version)/ $-40 \text{ }^{\circ}\text{C to } 85 \text{ }^{\circ}\text{C}$ (D version), unless otherwise specified.

Table 4.12 Power Supply Circuit Timing Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
t _{d(P-R)}	Time for internal power supply stabilization during power-on ⁽²⁾	—	—	—	2,000	μs

Notes:

1. The measurement condition is $V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$ and $T_{opr} = 25 \text{ }^{\circ}\text{C}$.
2. Wait time until the internal power supply generation circuit stabilizes during power-on.

Timing Requirements ($V_{CC} = 3\text{ V}$, $V_{SS} = 0\text{ V}$ at $T_{opr} = 25\text{ }^{\circ}\text{C}$, unless otherwise specified)

Table 4.21 External Clock Input (XIN)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_c(XIN)$	XIN input cycle time	50	—	ns
$t_{WH}(XIN)$	XIN input high width	24	—	ns
$t_{WL}(XIN)$	XIN input low width	24	—	ns

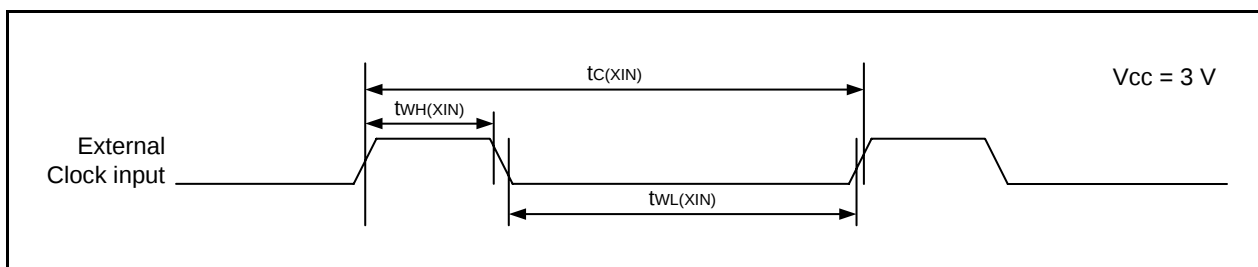


Figure 4.8 External Clock Input Timing When $V_{CC} = 3\text{ V}$

Table 4.22 TRJIO Input

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_c(TRJIO)$	TRJIO input cycle time	300	—	ns
$t_{WH}(TRJIO)$	TRJIO input high width	120	—	ns
$t_{WL}(TRJIO)$	TRJIO input low width	120	—	ns

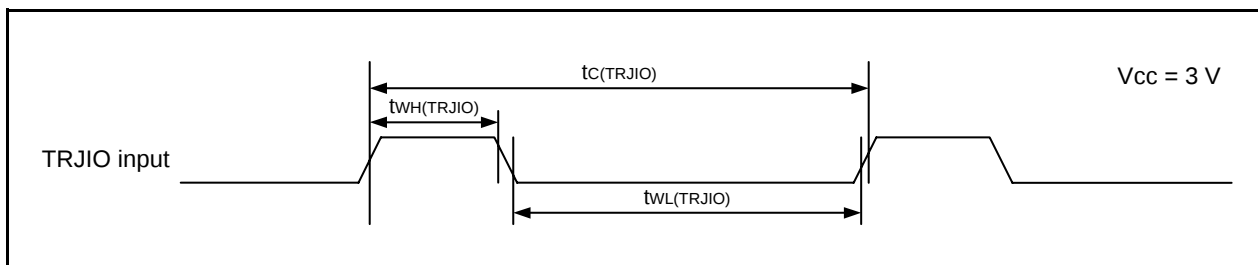
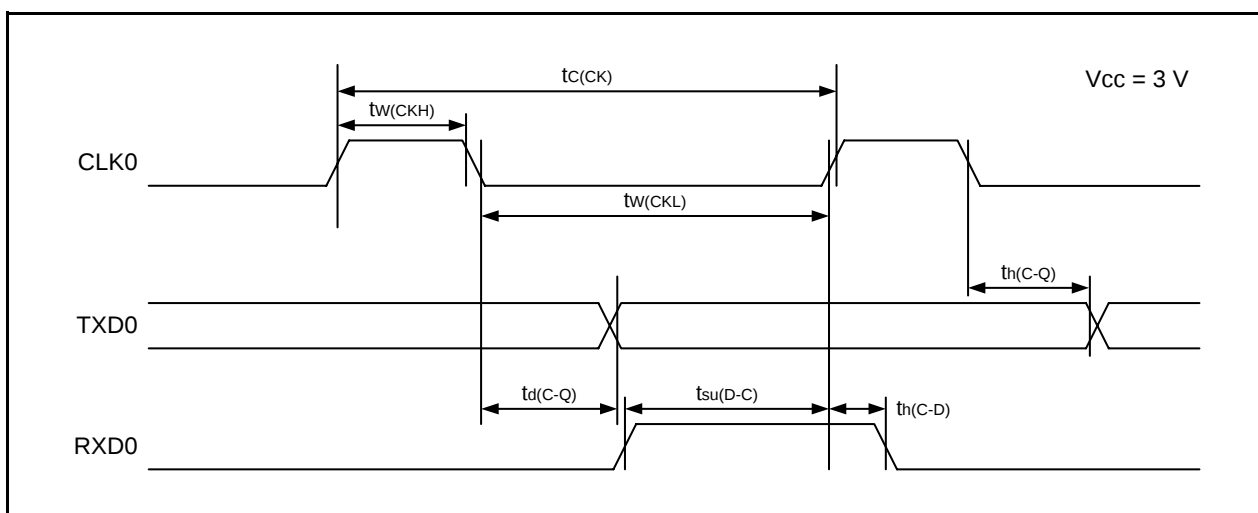


Figure 4.9 TRJIO Input Timing When $V_{CC} = 3\text{ V}$

Table 4.23 Serial Interface

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(CK)}$	CLK0 input cycle time	300	—	ns
$t_{w(CKH)}$	CLK0 input high width	150	—	ns
$t_{w(CKL)}$	CLK0 input low width	150	—	ns
$t_{d(C-Q)}$	TXD0 output delay time	—	80	ns
$t_{h(C-Q)}$	TXD0 hold time	0	—	ns
$t_{su(D-C)}$	RXD0 input setup time	70	—	ns
$t_{h(C-D)}$	RXD0 input hold time	90	—	ns

**Figure 4.10 Serial Interface Timing When $V_{CC} = 3\text{ V}$** **Table 4.24 External Interrupt $\overline{INTi}$ Input, Key Input Interrupt $\overline{Kli}$ ($i = 0$ to 3)**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(INH)}$	$\overline{INTi}$ input high width, $\overline{Kli}$ input high width	380 (1)	—	ns
$t_{w(INL)}$	$\overline{INTi}$ input low width, $\overline{Kli}$ input low width	380 (2)	—	ns

Notes:

1. When the digital filter is enabled by the $\overline{INTi}$ input filter select bit, the $\overline{INTi}$ input high width is $(1/\text{digital filter clock frequency} \times 3)$ or the minimum value of the standard, whichever is greater.
2. When the digital filter is enabled by the $\overline{INTi}$ input filter select bit, the $\overline{INTi}$ input low width is $(1/\text{digital filter clock frequency} \times 3)$ or the minimum value of the standard, whichever is greater.

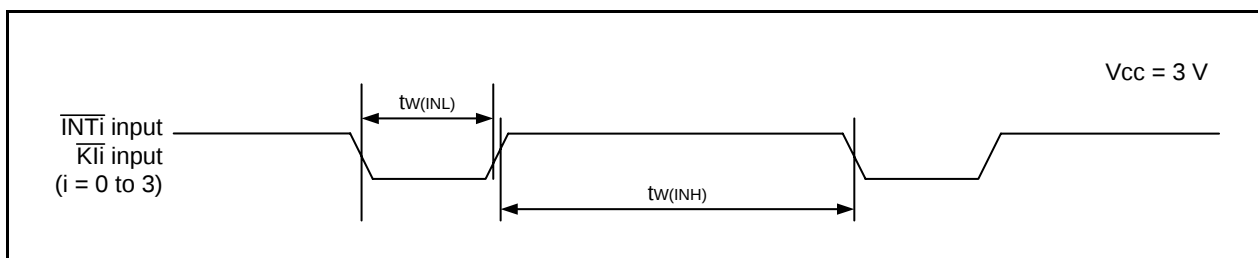
**Figure 4.11 Timing for External Interrupt $\overline{INTi}$ Input and Key Input Interrupt $\overline{Kli}$ When $V_{CC} = 3\text{ V}$**

Table 4.25 DC Characteristics (5) [$1.8\text{ V} \leq V_{CC} < 2.7\text{ V}$]

Symbol	Parameter		Condition		Standard			Unit
					Min.	Typ.	Max.	
V _{OH}	Output high voltage	P1_2, P1_3, P1_4, P1_5, P3_3, P3_4, P3_5, P3_7 (2)	When drive capacity is high	I _{OH} = -2 mA	V _{CC} - 0.5	—	V _{CC}	V
			When drive capacity is low	I _{OH} = -1 mA	V _{CC} - 0.5	—	V _{CC}	V
		P1_0, P1_1, P1_6, P1_7, P4_2, P4_5, P4_6, P4_7, PA_0		I _{OH} = -1 mA	V _{CC} - 0.5	—	V _{CC}	V
V _{OL}	Output low voltage	P1_2, P1_3, P1_4, P1_5, P3_3, P3_4, P3_5, P3_7 (2)	When drive capacity is high	I _{OL} = 2 mA	—	—	0.5	V
			When drive capacity is low	I _{OL} = 1 mA	—	—	0.5	V
		P1_0, P1_1, P1_6, P1_7, P4_2, P4_5, P4_6, P4_7, PA_0		I _{OL} = 1 mA	—	—	0.5	V
V _{T+} -V _{T-}	Hysteresis	INT0, INT1, INT2, INT3, KI0, KI1, KI2, KI3, TRJIO, TRCIOA, TRCIOB, TRCIOA, TRCIOB, RXD0, CLK0	V _{CC} = 2.2 V		0.05	0.20	—	V
		RESET	V _{CC} = 2.2 V		0.05	0.20	—	V
I _{IH}	Input high current		V _I = 2.2 V, V _{CC} = 2.2 V		—	—	4.0	μA
I _{IL}	Input low current		V _I = 0 V, V _{CC} = 2.2 V		—	—	-4.0	μA
R _{PULLUP}	Pull-up resistance		V _I = 0 V, V _{CC} = 2.2 V		70	140	300	kΩ
R _{FXIN}	Feedback resistance	XIN			—	2.2	—	MΩ
V _{RAM}	RAM hold voltage		In stop mode		1.8	—	—	V

Notes:

1. $1.8\text{ V} \leq V_{CC} < 2.7\text{ V}$ and Topr = -20 °C to 85 °C (N version)/-40 °C to 85 °C (D version), f(XIN) = 5 MHz, unless otherwise specified.
2. High drive capacity can also be used while the peripheral output function is used.

Timing Requirements ($V_{CC} = 2.2\text{ V}$, $V_{SS} = 0\text{ V}$ at $T_{opr} = 25\text{ }^{\circ}\text{C}$, unless otherwise specified)

Table 4.27 External Clock Input (XIN)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_c(XIN)$	XIN input cycle time	200	—	ns
$t_{WH}(XIN)$	XIN input high width	90	—	ns
$t_{WL}(XIN)$	XIN input low width	90	—	ns

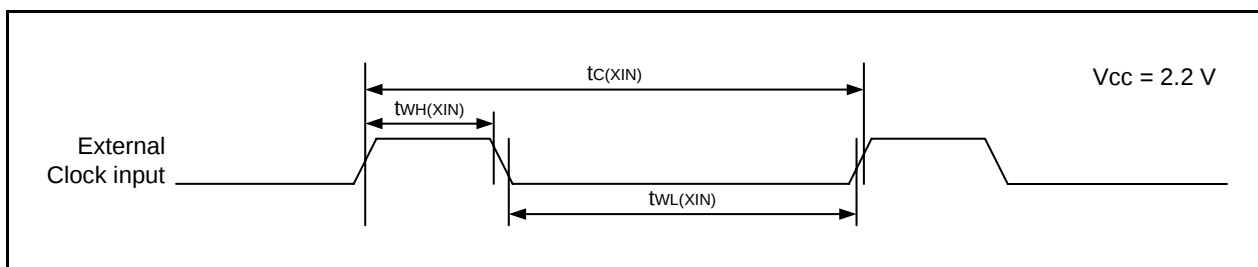


Figure 4.12 External Clock Input Timing When $V_{CC} = 2.2\text{ V}$

Table 4.28 TRJIO Input

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_c(TRJIO)$	TRJIO input cycle time	500	—	ns
$t_{WH}(TRJIO)$	TRJIO input high width	200	—	ns
$t_{WL}(TRJIO)$	TRJIO input low width	200	—	ns

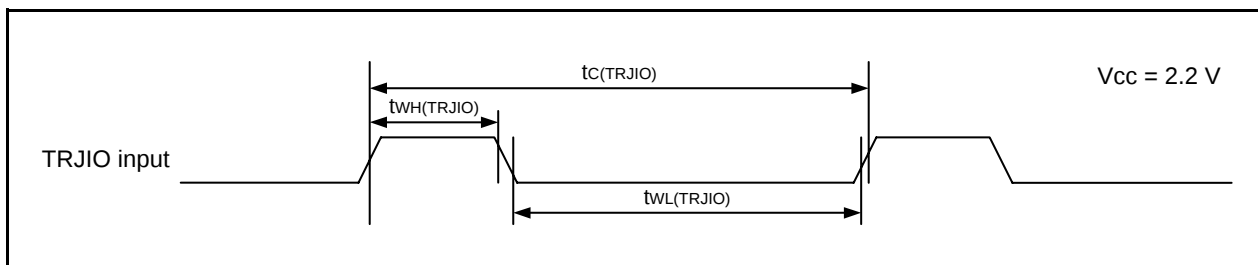
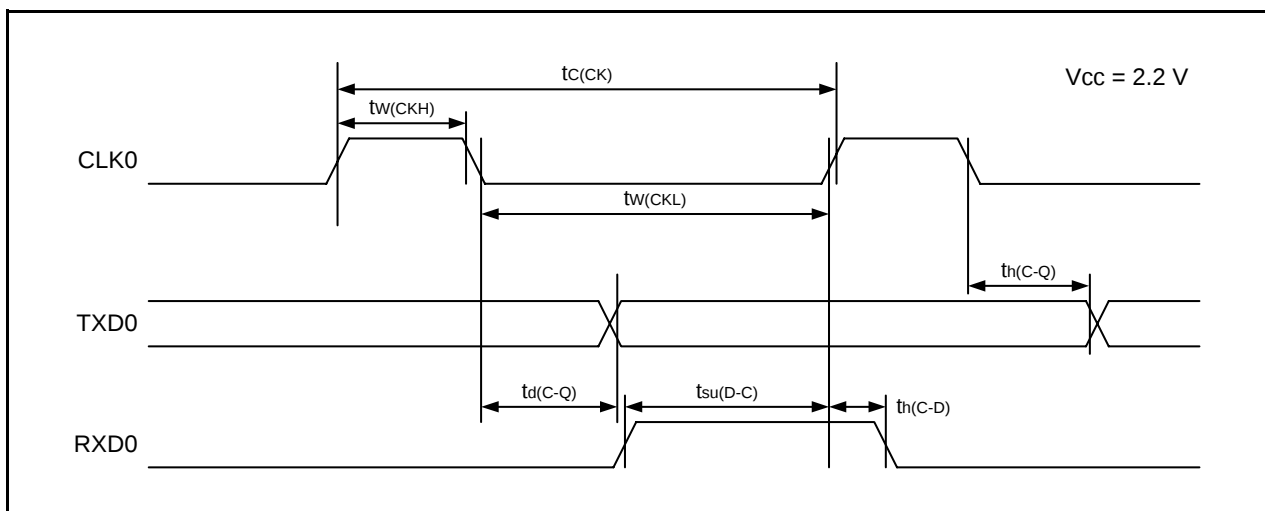


Figure 4.13 TRJIO Input Timing When $V_{CC} = 2.2\text{ V}$

Table 4.29 Serial Interface

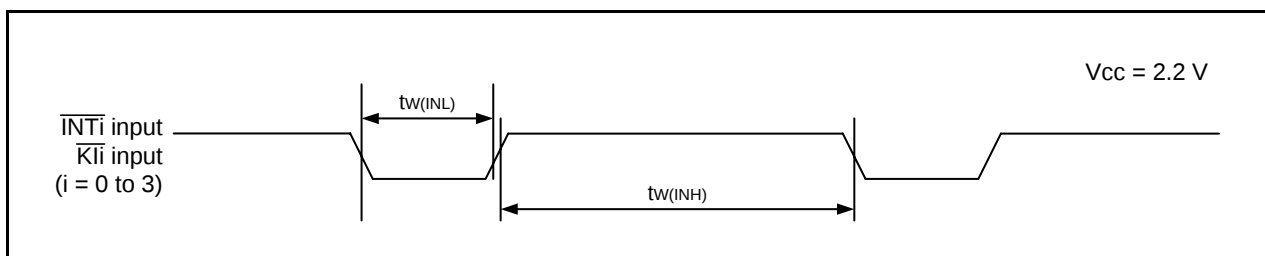
Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(CK)}$	CLK0 input cycle time	800	—	ns
$t_{w(CKH)}$	CLK0 input high width	400	—	ns
$t_{w(CKL)}$	CLK0 input low width	400	—	ns
$t_{d(C-Q)}$	TXD0 output delay time	—	200	ns
$t_{h(C-Q)}$	TXD0 hold time	0	—	ns
$t_{su(D-C)}$	RXD0 input setup time	150	—	ns
$t_{h(C-D)}$	RXD0 input hold time	90	—	ns

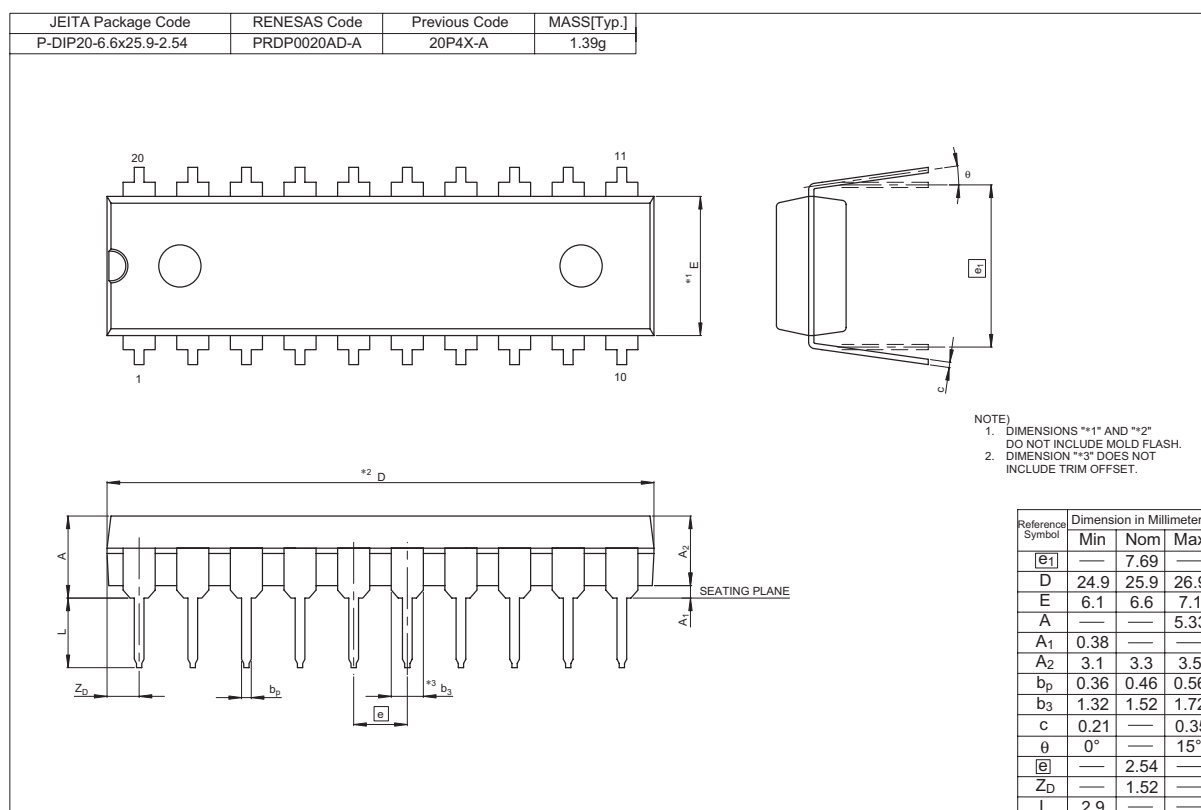
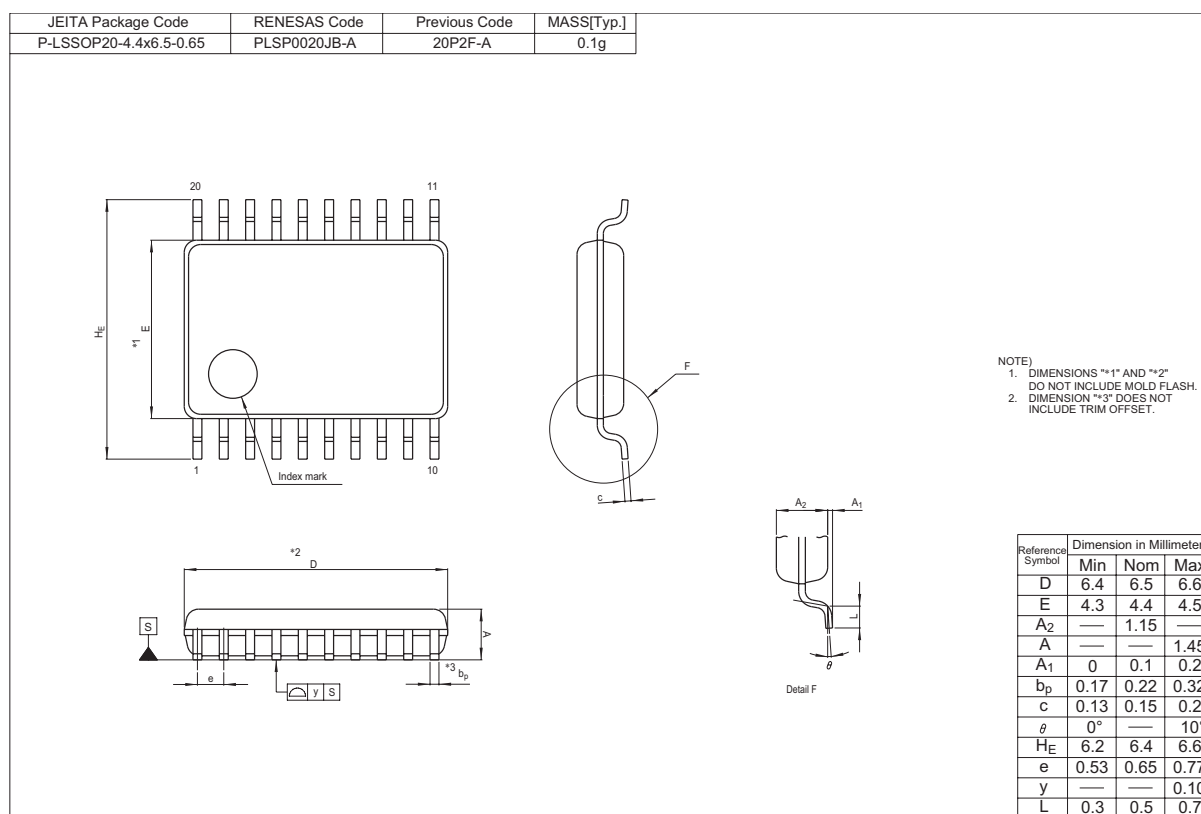
**Figure 4.14 Serial Interface Timing When $V_{CC} = 2.2\text{ V}$** **Table 4.30 External Interrupt $\overline{INTi}$ Input, Key Input Interrupt $\overline{Kli}$ ($i = 0$ to 3)**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(INH)}$	$\overline{INTi}$ input high width, $\overline{Kli}$ input high width	1,000 (1)	—	ns
$t_{w(INL)}$	$\overline{INTi}$ input low width, $\overline{Kli}$ input low width	1,000 (2)	—	ns

Notes:

1. When the digital filter is enabled by the $\overline{INTi}$ input filter select bit, the $\overline{INTi}$ input high width is $(1/\text{digital filter clock frequency} \times 3)$ or the minimum value of the standard, whichever is greater.
2. When the digital filter is enabled by the $\overline{INTi}$ input filter select bit, the $\overline{INTi}$ input low width is $(1/\text{digital filter clock frequency} \times 3)$ or the minimum value of the standard, whichever is greater.

**Figure 4.15 Timing for External Interrupt $\overline{INTi}$ Input and Key Input Interrupt $\overline{Kli}$ When $V_{CC} = 2.2\text{ V}$**



REVISION HISTORY	R8C/M11A Group, R8C/M12A Group Datasheet
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Rev.	Date	Description	
		Page	Summary
0.01	Jan 14, 2010	—	First Edition issued
0.10	Aug 25, 2010	— 2, 3 4 5 6 8 9 11 to 43	Document No. "REJ03B0308" → "R01DS0010EJ" 1.1.2 Differences between Groups added Table 1.3 "Reset by voltage detection 0" deleted Table 1.4 "... ROM: VCC = 2.7 V to 5.5 V" → "... ROM: VCC = 1.8 V to 5.5 V", "1,000 times (program ROM)" → "10,000 times (program ROM)", Note 1 added Table 1.5 revised Figures 1.3 and 1.4 revised Table 1.6 revised 2. Central Processing Unit (CPU), 3. Address Space, 4. Electrical Characteristics added
1.00	May 31, 2012	All pages 1 3 4 5 6 10 15 18 23 26 31 45	"Preliminary" and "Under development" deleted 1.1 revised Table 1.2 revised Table 1.3 revised Table 1.4 Note 1 revised Table 1.5 revised Table 1.7 revised Table 3.1 revised Table 3.4 revised Table 3.9 Notes 1 and 2 revised Table 4.3 revised Table 4.10 and 4.11 revised, Note3 deleted Package added
2.00	May 31, 2012	4 9 26	"Under development" deleted Table 1.6 "Voltage detection circuit" deleted Table 4.3 revised

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